DOCUMENT CHANGE REQUEST

DCR number 1377	Changes required for: General	Originator: Steve Jeffery
Date: 2021/07/16	Date sent: 2020/09/17	Organisation: ESCC Executive
Status: IMPLEMENTED		

Title:	Evaluation Test Programme for Discrete Non-Microwave Semiconductors		
Number:	2265000	Issue:	3

Other documents affected:

Page:

11, 12, 18, 21

Paragraph:

7.3.2.4, 7.3.2.5, NEW 7.3.2.6 (existing 7.3.2.6 is re-numbered: 7.3.2.7), 8.10.2, 8.10.3, Chart I.

Original wording:

See ESCC 2265000 Issue 3.

Proposed wording:

As highlighted in yellow in the attachment ESCC226500 Draft4A for DCR review.docx

Justification:

As required by PSWG & ESA review of IOL within ESCC 2265000 (as alternate test to Temperature / Power Step-Stress, on a case-by-case discussion basis with the ESCC Executive)

Attachments:

escc2265000_draft4a_for_dcr_review.docx, escc2265000_draft4c_(ref_dcr1377)_in_review.docx

Modifications:

The original DCR contents is replaced by the following:

Paragraphs:
See attached Draft 4C with changes to Paras: 4.1, 7.3.2.1, 7.3.2.4, 7.3.2.5, new 7.3.2.6, 7.3.2.7, 8.1, 8.10.2, new 8.10.4, Chart I

Proposed wording:
See attached Draft 4C (yellow and blue highlights for changes).

Justification:
As concluded by PSWG#94 review of this DCR1377:

The existing Temperature & Power Step-Stress tests are effectively made optional based on technology (subject to Manufacturer & ESCC Executive review).

Also based on technology: The addition of an optional 10000 cycles intermittent operating life test to the step-stress testing subgroup per MIL-19500 requirements, also subject to Manufacturer and ESCC Executive review.

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Approval signature:



Date signed:

2021-07-16